

Notice of References Cited

Application/Control No.

10/510,977

Applicant(s)/Patent Under
Reexamination
YAMAUCHI ET AL.

Examiner

Thuy V. Tran

Art Unit

2821

Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-6,975,286 B2 | 12-2005 | Rhee, Byung Joon | 345/60 |
| * | B | US-6,630,796 B2 | 10-2003 | Tokunaga et al. | 315/169.4 |
| * | C | US-6,337,673 B1 | 01-2002 | Ide et al. | 345/60 |
| * | D | US-6,144,163 | 11-2000 | Amemiya et al. | 315/169.1 |
| * | E | US-6,037,916 | 03-2000 | Amemiya, Kimio | 345/60 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.